## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | MURAKAMI ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0012406 A1	01-2003	Iwamura, Keiichi	382/100
*	В	US-2003/0025805 A1	02-2003	Yamagishi, Yoichi	348/222.1
*	С	US-6,532,541 B1	03-2003	Chang et al.	713/176
*	D	US-2003/0133591 A1	07-2003	Watanabe et al.	382/100
	E	US-			
	F	US-			
	G	US-			•
	Н	US-			
	ı	US-			
	J	US-		·	
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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